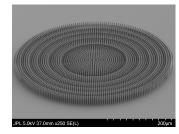
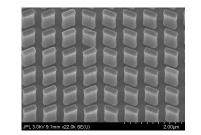


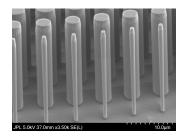
#### **Metasurface fabrication**

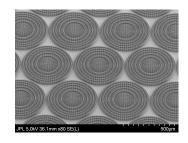
<u>Tobias Wenger</u> Jet Propulsion Laboratory, California Institute of Technology

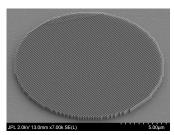








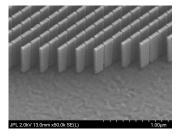


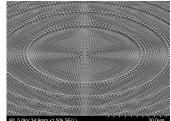


# Outline

- Microfabrication 101
  - Patterning (lithography)
  - Material deposition (evaporation, sputtering, atomic-layer deposition)
  - Material removal (etching)
  - (Surface preparation, surface cleaning, handling, dicing, material interactions...)
- Metasurface fabrication examples
- Challenges
  - Material selection
  - Resolution and Aspect Ratio
  - More challenges..







## **Patterning - microlithography**

"Make or break bonds in a resist."

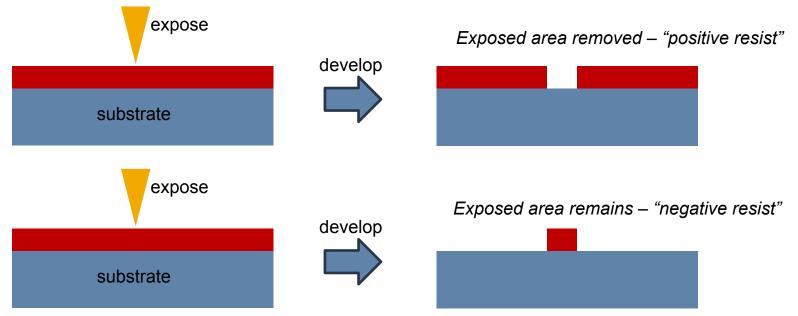
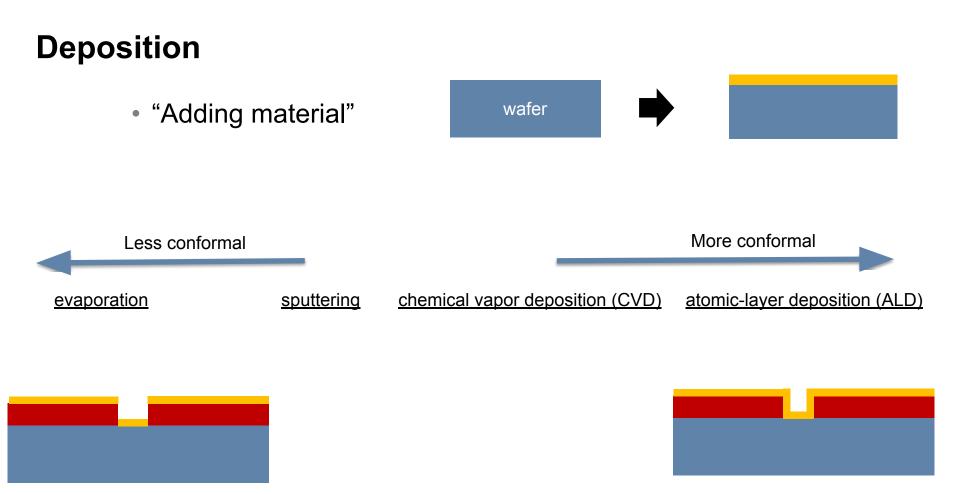


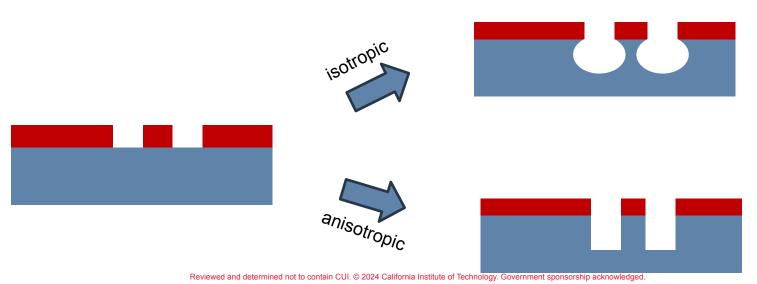
Photo-lithography vs electron-beam lithography



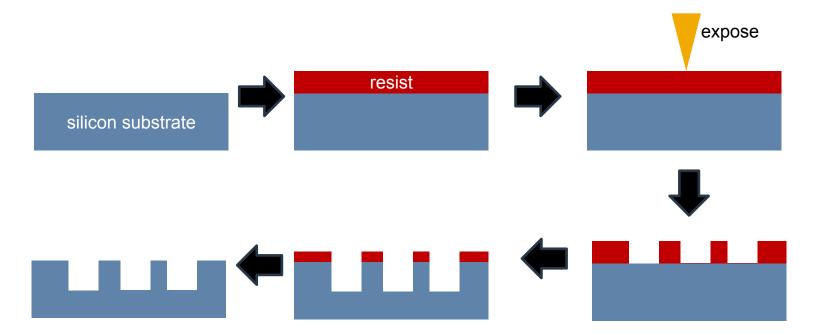
Reviewed and determined not to contain CUI. © 2024 California Institute of Technology. Government sponsorship acknowledged.

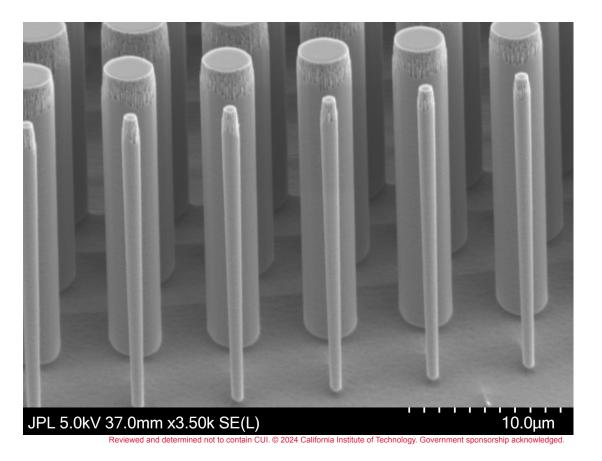
## Etching

- "Removing material"
- Wet etch vs dry (plasma) etch
- Isotropic vs anisotropic
- Selectivity

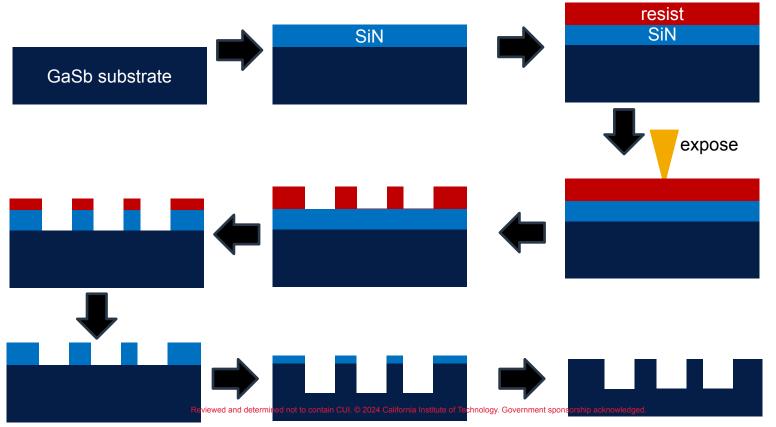


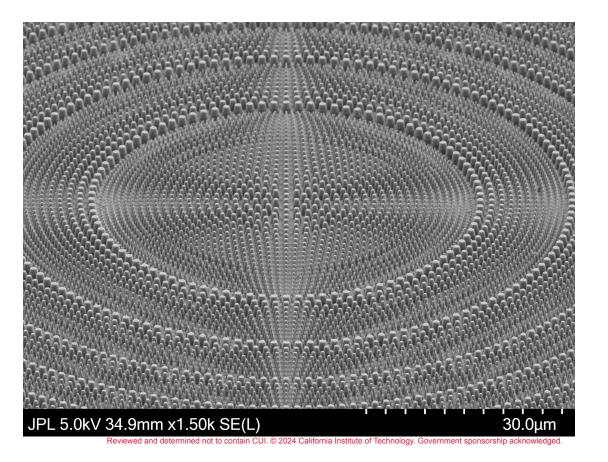
Silicon metasurface – photoresist mask



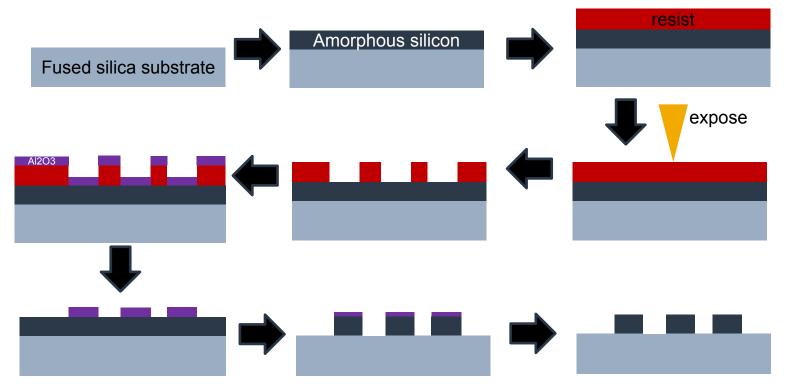


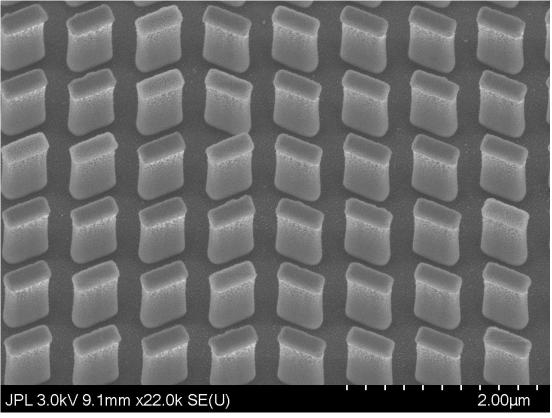
GaSb metasurface – SiN hardmask



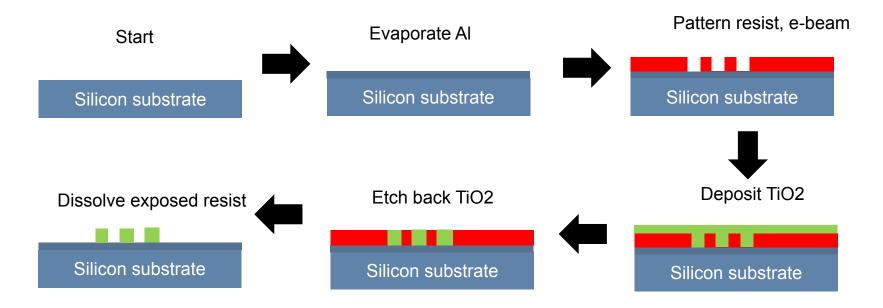


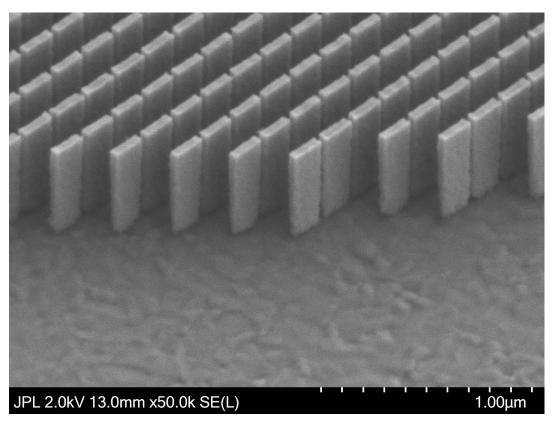
Amorphous silicon metasurface on fused silica, Al2O3 hardmask





TiO2 metasurface on aluminum



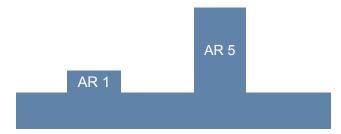


#### Materials and wavelength

- Silicon is a common material choice for microprocessing.
  - Accessible, low cost, easy handling, well developed etch chemistry (SF6/C4F8)
  - High refractive index, n=3.4. Meaning 50% of light lost from entering/exiting substrate.
    - One mitigation strategy is to use amorphous silicon (aSi) on fused silica.
  - Not transparent below ~1 micron.
    - Use other materials transparent below 1 micron (SiO2, SiN, TiO2, diamond, sapphire...)
- Use of other materials than silicon may require significant process development.

### **Resolution and aspect ratio**

- Resolution describes the ability to print or otherwise make small features.
- Aspect Ratio (AR) describes the height-to-width ratio of a structure (often the critical dimension, CD, is used for calculating AR).
- Resolution and AR are often inter-related.
- For example, typically more challenges involved when targeting 20 nm resolution in a 100 nm tall feature (AR 5), than in a 20 nm tall feature (AR 1).
- Aspect-ratio dependent etch rate.

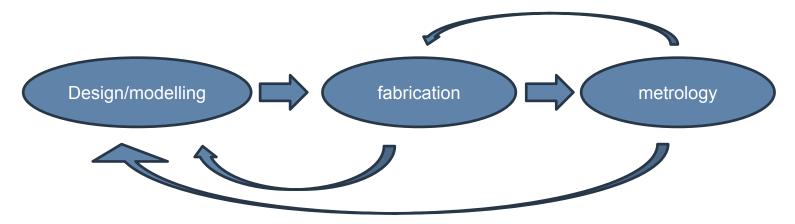


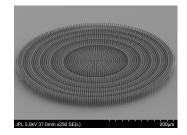
### Challenges

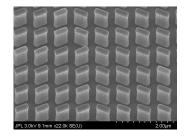
- Aspect-ratio dependent etch rate
- Depth-dependent etch profile
- Non-uniformities in deposition rate and/or etch rate
- Tool performance "drifts" over time (and/or rapidly changes due certain processes being run before)
- Particle contamination

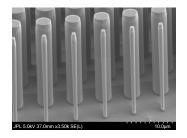
## **Closing thoughts**

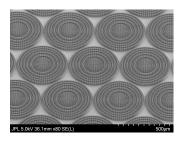
- To succeed in making high-precision optical metasurfaces, in my view several things are needed:
  - an understanding of metasurface design tolerances
  - a good way of measuring metasurface performance
  - a willingness to iterate on design, fabrication and metrology

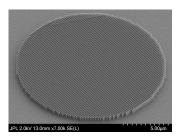














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# Thank you!



